

EXTERNAL SERIAL ATA CONNECTOR / 1.27mm PITCH

1.0 SCOPE

This Product Specification covers the mechanical, electrical and environmental performances requirements and test methods for external Serial-ATA connector series products.

2.0 APPLICABLE DOCUMENTS AND SPECIFICATIONS

The following documents form a part of this specification to the extent specified herewith. In the event of conflict between the requirements of the specification and the product drawing, the product drawing shall take precedence. In the event of conflict between the requirements of the specification and the referenced documents, this specification shall take precedence.

2.1 EIA 364 Test Methods for Electronic and Electrical Component Parts

2.2 External serial ATA / High Speed Serialized at Attachment Specification

3.0 MATERIAL SPECIFICATIONS

3.1 Design and Construction

Connector shall be of the design, construction and physical dimensions specified on the applicable sales drawing.

3.2 Materials

- a) Contacts: Refer to respective Molex sales & engineering drawings
- b) Housing: Refer to respective Molex sales & engineering drawings
- c) Plating: Refer to respective Molex sales & engineering drawings

4.0 PERFORMANCE AND TEST DESCRIPTION

4.1 Performance requirement:

Connector shall be designed to meet the electrical, mechanical and environmental performances requirements specified in 5.0

4.2 VOLTAGE:

15V DC

- 4.3 CURRENT: 1.5A DC @25°C
- 4.4 TEMPERATURE

Operating Temperature Range: Storage Temperature Range:

-35°C to +85°C (Without loss function) -35°C to +85°C (Without loss function)

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5.0 Test Requirements and Procedures.

5.1 ELECTRICAL REQUIREMENTS

	DESCRIPTION	TEST CONDITION	REQU	IREMENT		
5.1.1	Insulation Resistance	EIA 364-21 After 500 VDC for 1 minute, measinsulation resistance between the a contacts of mated and unmated co assemblies.	adjacent 1000 Mega of	1000 Mega ohms MINIMUM		
5.1.2	Dielectric Withstanding Voltage	EIA 364-20 Method B Test between adjacent contacts of and unmated connector assemblie	mated 500 VAC for 1	shall withstand minute sea level		
5.1.3	Contact Resistance (LLCR)	EIA 364-23 Subject mated contacts assembled housing to 20 mV maximum open 100 mA maximum.	circuit at 2. Resistance	 Initially 30 milliohms Max. Resistance increased 15 milliohms Max. after stress 		
5.1.4	Mated connector impedance (Signal Port)	 Set the Time Domain Reflectom (TDR) pulsers in differential mod positive going (V+) and a negative pulse (V-). Define a reflected difference: Vdiff = V+ - V- With the TDR connected to the mass reference trace, verify an input rise of 70 ps (measured 20% - 80% Verifting may be used to slow the sedown (see NOTE 2) Connect the TDR to the sample measurement traces. Calibrate the instrument and system (see NOTE 4). Measure and record the maximum minimum values of the near end connector impedance. 	e with a re going erential isetime setime /p). ystem 100 ohm +/- 1 ne 'E 3).	5%		
5.1.5	Contact current rating (Power segment)	 connector impedance. I. Mount the connector to a test PCB 2. Wire power pins P2, P3, P5 and P6 in parallel for power 3. Wire ground pins P1, P4 and P7 in parallel for return 4. Supply 6A total DC current to the power pins in parallel, returning from the parallel ground pins (P1, P4 and P7) 5. Record temperature rise when thermal equilibrium is reached 				
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NOTES-

1. Time domain measurement equipment allows for delay adjustment of the pulses so launch times can be synchronized. Frequency domain equipment will require the use of phase matched fixturing .The fixturing skew should be verified to be <1 ps on a TDR.

2. The system rise time is to be set via equipment filtering techniques. The filter risetime is significantly close to the stimulus risetime. Therefore the filter programmed equals the square root of $(t_{r(observed)})$ squared - $(t_{r(stimulus)})$ squared. After filtering, verify the risetime is achieved using the risetime reference traces on the PCB fixture.

3. Calibrate the system by substituting either precision 50-ohm loads or precision air lines (also terminated in 50 ohm loads) for the test fixture. This places the calibration plane directly at the input interface of the test fixture.

	DESCRIPTION	TEST CONDITION	REQUIREMENT
5.2.1	Visual and dimensional inspections	EIA 364-18 Visual, dimensional and functional per applicable quality inspection plan.	Meet product drawing requirements.
5.2.2	Insertion force	EIA 364-13 Measure the force necessary to mate the connector assemblies at a max. rate of 12.5 mm(0.492") per minute.	20 N MAXIMUM
5.2.3	Removal force	EIA 364-13 Measure the force necessary to unmate the connector assemblies at maximun rate of 12.5 mm(0.492") per miniute.	4 N MINMUN through 500 cycles
5.2.4	Durability	EIA 364-09 2500 cycles for external cabled application; Test done at a Maximum rate of 200 cycles per hour.	No physical damage. Meet requirements of additional tests as specified in the test sequence

5.2 MECHANICAL REQUIREMENTS

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5.3 ENVIRONMENTAL REQUIREMENTS

i	DESCRIPTION	TEST CONDITION	REQUIREMENT			
5.3.1	Physical shock	EIA 364-27 Condition H Subject mated connector to 30 g's half-sine shock pulses of 11 msec duration. Three shocks in each direction applied along three mutually perpendicular planes for a total 18 shocks. See NOTE 2.	No discontinuities of 1 ms or longer duration. No physical damage.			
5.3.2	Random vibration	EIA 364-28 Condition V Test letter A Subject mated connectors to 5.35 g's RMS. 30 minutes in each of three mutually perpendicular planes. See Note 2.	No discontinuities of 1 µs or longer duration.			
5.3.3	Humidity	EIA 364-31 Method II Test Condition A. Subject mated connectors to 96 hours at 40 [°] C with 90% to 95% RH	See NOTE 1			
5.3.4	Temperature life	EIA 364-17 Test Condition III Method A. Subject mated connectors to temperature life at +85 ^o C for 500 hours.	See NOTE 1			
5.3.5	Thermal shock	EIA 364-32 Test Condition I. Subject mated connectors to 10 cycles between -55 $^{\circ}$ C and +85 $^{\circ}$ C.	See NOTE 1			
5.3.6	Mixed Flowing Gas	EIA 364-65, Class 2A Half of the samples are exposed unmated for seven days, then mated for remaining seven days. Other half of the samples are mated during entire testing	See NOTE 1			
 NOTE- Shall meet EIA 364-18 Visual Examination requirements, show no physical damage, and shall meet requirements of additional tests as specified in the test sequences table. Shock and vibration test fixture is to be determined by each user with connector vendors. 						
1.	Shall meet EIA 364- shall meet requireme	ents of additional tests as specified in the te	est sequences table.			
1.	Shall meet EIA 364- shall meet requireme	N: TITLE: EXTERNAL SERIAL ATA	est sequences table. er with connector vendors.			

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5.4 SOLDERING CONDITION

5.4.1 Wave Soldering:

Recommended Soldering Temperature: 217°C Min, 90 Seconds Min.

5.4.2 Recommended IR Profile:

Condition
>100°C
>150°C
>217°C
within 5°C of Peak
Peak Temperature
Average ramp-up rate (25°C to 217°C)
Cool-down rate (Peak to 50°C)
Time from 25°C to Peak

Exposure 360~600 seconds at least 240 seconds at least 90 seconds 20~40 seconds Great than or equal to 255°C Less than 3°C /seconds Less than 6°C /seconds No great than 480 seconds

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5.5 Group Test Item (5 pieces per group)

Test Sequence Groups	Α	В	С	D	E
Sample group sizes	5	5	5	5	5
Examination of connector(s)	1,5	1,9	1,8	1,8	1,7
Low-Level Contact Resistance (LLCR)	2,4	3,7	2,4,6		4,6
Insulation resistance				2,6	
Dielectric withstanding voltage				3,7	
Current rating			7		
Insertion force		2			
Removal force		8			
Durability	3	4(a)			2(a)
Physical shock		6			
Vibration		5			
Humidity				5	
Temperature life			3		
Reseating (manually unplug/plug three times)			5		5
Mixed Flowing Gas					3
Thermal shock				4	
NOTE -		J	1		<u>ų</u>

(a) Preconditioning, 50 cycles for the 2500-durability cycle requirement.

(b) The insertion and removal cycle is at the Maximum rate of 200 cycles per hour.

6.0 PACKAGING

Parts shall be packaged to protect against damage during handling, transit and storage.

7.0 OTHER INFORMATION

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